

**Notice of References Cited**

Application/Control No.

09/774,555

Applicant(s)/Patent Under  
Reexamination  
DELONG ET AL.

Examiner

Barbara P Badio, Ph.D.

Art Unit

1616

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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X	N	WO 99/12895	03-1999	WO	Wos et al.	-
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